

Search Notes

Application/Control No.

10/761,822

Examiner

John A. Tweel, Jr.

Applicant(s)/Patent under
Reexamination

LEE, YONG

Art Unit

2636

SEARCHED

Class	Subclass	Date	Examiner
340	465	5/13/2005	JAT
	464	5/13/2005	JAT
	463	5/13/2005	JAT
	471	5/13/2005	JAT
	472	5/13/2005	JAT
	473	5/13/2005	JAT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR